

Application/Control No.	Applicant(s)/Patent und Reexamination	der
09/769,908	MATSUHIRA ET AL.	
Examiner	Art Unit	
John I Shew	2664	

-	SEAR	CHED	
Class	Subclass	Date	Examiner
370	216-218	8/15/2005	JS
	228,237		
-	238.1		
	255-258		
	295		
	351,352		
	355,389		
	392		
	395.1		
	395.31		
	395.32		
	396-400		
	401-404		
379	221.03	8/15/2005	JS

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
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(INCLUDING SEAR	DATE	EXMR
	DATE	EXWIR
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Search Notes (continued)

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09/769,908	MATSUHIRA ET AL.	
Examiner	Art Unit	
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	SEAR	CHED	
Class	Subclass	Date	Examiner
379	221.04	8/15/2005	JS
709	238,239	8/15/2005	JS

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR